

Notice of References Cited	Application/Control No. 10/671,008	Applicant(s)/Patent Under Reexamination DEXTRAZE ET AL.	
	Examiner Stephen F. Gerrity	Art Unit 3721	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-D395,780	07-1998	Denney et al.	D6/596
*	B	US-3,307,319	03-1967	CHRISTENSEN GORDON L; et. al.	53/434
*	C	US-3,458,966	08-1969	Dunbar et al.	53/430
*	D	US-3,521,424	07-1970	WIRFEL EMANUEL W	53/419
*	E	US-3,827,210	08-1974	Smalley et al.	53/434
*	F	US-3,935,690	02-1976	Lea et al.	53/397
*	G	US-4,108,063	08-1978	Randolph, Arthur J.	100/352
*	H	US-4,841,713	06-1989	Beier, John K.	53/413
*	I	US-5,027,578	07-1991	Natterer et al.	53/86
*	J	US-5,097,648	03-1992	Berner et al.	53/88
*	K	US-5,832,701	11-1998	Hauers et al.	53/551
*	L	US-2003/0183550	10-2003	DiLiberto, Samuel L. JR.	206/524.8
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 03200515 A	09-1991	Japan	OKAWA, HIDEO	B65B 31/04
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.